



YOUSHANG SEMICONDUCTOR

**设计研发新型功率器件**

**各类小信号开关**

**中低压及高压大电流等场效应管**

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企业微信二维码



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## Product Summary

Device	BV <sub>DSS</sub>	R <sub>DS(ON)</sub> Max	I <sub>D</sub> T <sub>A</sub> = +25°C
Q1	40V	24mΩ @ V <sub>GS</sub> = 10V	8.3A
		32mΩ @ V <sub>GS</sub> = 4.5V	7.2A
Q2	-40V	45mΩ @ V <sub>GS</sub> = -10V	-6.1A
		55mΩ @ V <sub>GS</sub> = -4.5V	-5.5A

## Description

This new generation MOSFET is designed to minimize the on-state resistance (R<sub>DS(ON)</sub>), yet maintain superior switching performance, making it ideal for high efficiency power management applications.

## Applications

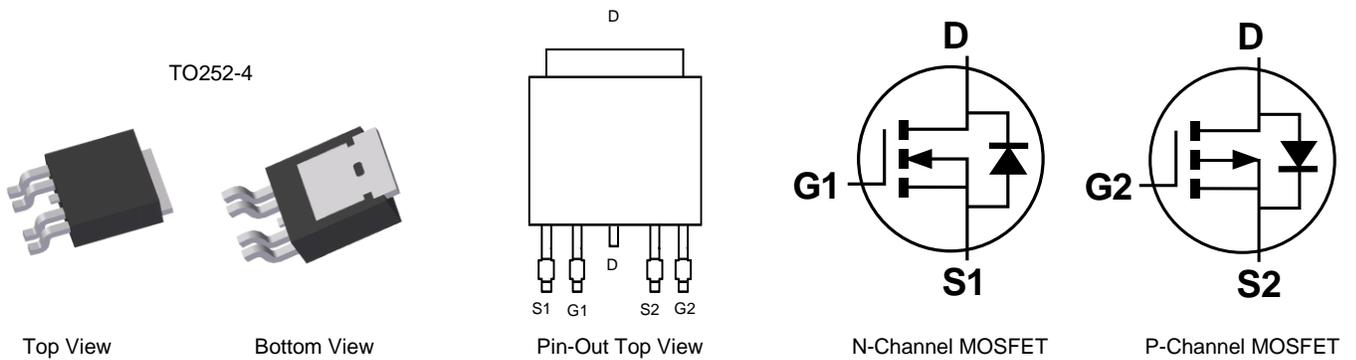
- DC-DC Converters
- Power Management Functions
- Backlighting

## Features and Benefits

- Low Input Capacitance
- Low On-Resistance
- Fast Switching Speed

## Mechanical Data

- Case: TO252-4
- Case Material: Molded Plastic, "Green" Molding Compound.  
UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See Diagram
- Terminals: Finish – Matte Tin Annealed over Copper Leadframe.  
Solderable per MIL-STD-202, Method 208 @3
- Weight: 0.34 grams (Approximate)



**Maximum Ratings** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic			Symbol	Value_Q1	Value_Q2	Unit
Drain-Source Voltage			$V_{DSS}$	40	-40	V
Gate-Source Voltage			$V_{GSS}$	$\pm 20$	$\pm 20$	V
Continuous Drain Current (Note 6) $V_{GS} = 10\text{V}$	Steady State	$T_A = +25^\circ\text{C}$ $T_A = +70^\circ\text{C}$	$I_D$	8.3 6.7	-6.1 -4.9	A
	$t < 10\text{s}$	$T_A = +25^\circ\text{C}$ $T_A = +70^\circ\text{C}$	$I_D$	11.8 9.4	-8.6 -6.9	A
Maximum Body Diode Forward Current (Note 6)			$I_S$	2.5	-2.5	A
Pulsed Drain Current (10 $\mu\text{s}$ Pulse, Duty Cycle = 1%)			$I_{DM}$	45	-35	A
Avalanche Current, $L = 0.1\text{mH}$ (Note 8)			$I_{AS}$	21	-20	A
Avalanche Energy, $L = 0.1\text{mH}$ (Note 8)			$E_{AS}$	22	20	mJ

**Thermal Characteristics** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 5)	$T_A = +25^\circ\text{C}$	$P_D$	1.5	W
	$T_A = +70^\circ\text{C}$		1.0	
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	$R_{\theta JA}$	88	$^\circ\text{C/W}$
	$t < 10\text{s}$		40	
Total Power Dissipation (Note 6)	$T_A = +25^\circ\text{C}$	$P_D$	2.9	W
	$T_A = +70^\circ\text{C}$		1.6	
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{\theta JA}$	42	$^\circ\text{C/W}$
	$t < 10\text{s}$		20	
Thermal Resistance, Junction to Case (Note 7)		$R_{\theta JC}$	4.5	
Operating and Storage Temperature Range		$T_J, T_{STG}$	-55 to +150	$^\circ\text{C}$

**Electrical Characteristics — Q1 N-Channel** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

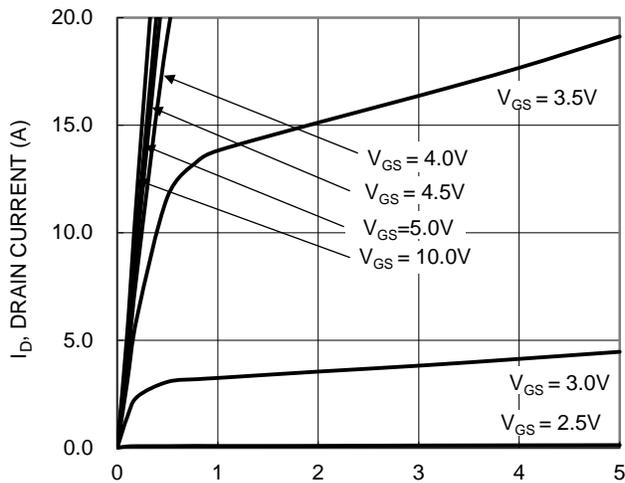
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS</b> (Note 9)						
Drain-Source Breakdown Voltage	$BV_{DSS}$	40	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
Zero Gate Voltage Drain Current	$I_{DSS}$	—	—	1	$\mu\text{A}$	$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	$I_{GSS}$	—	—	$\pm 100$	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$
<b>ON CHARACTERISTICS</b> (Note 9)						
Gate Threshold Voltage	$V_{GS(TH)}$	1.0	—	3.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	15	24	m $\Omega$	$V_{GS} = 10\text{V}, I_D = 6\text{A}$
		—	20	32		$V_{GS} = 4.5\text{V}, I_D = 5\text{A}$
Diode Forward Voltage	$V_{SD}$	—	0.7	1.0	V	$V_{GS} = 0\text{V}, I_S = 1.0\text{A}$
<b>DYNAMIC CHARACTERISTICS</b> (Note 10)						
Input Capacitance	$C_{ISS}$	—	1,060	—	pF	$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Output Capacitance	$C_{OSS}$	—	84	—		
Reverse Transfer Capacitance	$C_{RSS}$	—	58	—		
Gate Resistance	$R_G$	—	1.6	—	$\Omega$	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Total Gate Charge ( $V_{GS} = 4.5\text{V}$ )	$Q_G$	—	8.8	—	nC	$V_{DS} = 20\text{V}, I_D = 8\text{A}$
Total Gate Charge ( $V_{GS} = 10\text{V}$ )	$Q_G$	—	19.1	—		
Gate-Source Charge	$Q_{GS}$	—	3.0	—		
Gate-Drain Charge	$Q_{GD}$	—	2.5	—		
Turn-On Delay Time	$t_{D(ON)}$	—	5.3	—	ns	$V_{DD} = 25\text{V}, R_L = 2.5\Omega, V_{GS} = 10\text{V}, R_G = 3\Omega$
Turn-On Rise Time	$t_R$	—	7.1	—		
Turn-Off Delay Time	$t_{D(OFF)}$	—	15.1	—		
Turn-Off Fall Time	$t_F$	—	4.8	—		
Body Diode Reverse Recovery Time	$t_{RR}$	—	10.5	—	ns	$I_F = 8\text{A}, di/dt = 100\text{A}/\mu\text{s}$
Body Diode Reverse Recovery Charge	$Q_{RR}$	—	4.15	—	nC	$I_F = 8\text{A}, di/dt = 100\text{A}/\mu\text{s}$

**Electrical Characteristics — Q2 P-Channel** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

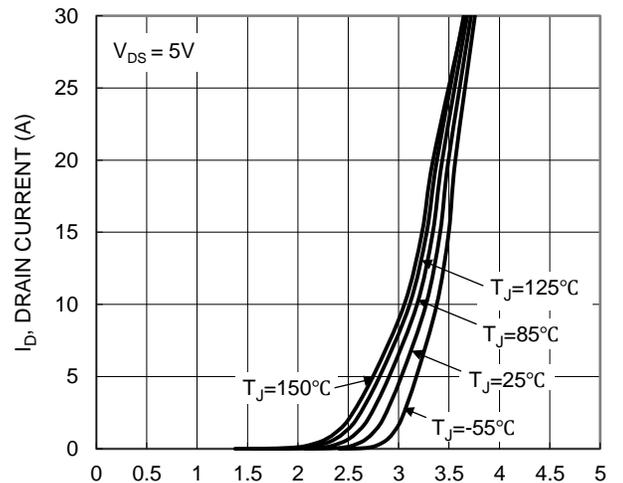
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS</b> (Note 9)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-40	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	—	—	-1	μA	V <sub>DS</sub> = -40V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	—	—	±100	nA	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS</b> (Note 9)						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	-1.0	—	-3.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	—	33	45	mΩ	V <sub>GS</sub> = -10V, I <sub>D</sub> = -5A
		—	40	55		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -4A
Diode Forward Voltage	V <sub>SD</sub>	—	-0.7	-1.0	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -1.0A
<b>DYNAMIC CHARACTERISTICS</b> (Note 10)						
Input Capacitance	C <sub>ISS</sub>	—	1,154	—	pF	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V f = 1.0MHz
Output Capacitance	C <sub>OSS</sub>	—	84	—		
Reverse Transfer Capacitance	C <sub>RSS</sub>	—	66	—		
Gate Resistance	R <sub>G</sub>	—	12.6	—	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1.0MHz
Total Gate Charge (V <sub>GS</sub> = -4.5V)	Q <sub>G</sub>	—	10.6	—	nC	V <sub>DS</sub> = -20V, I <sub>D</sub> = -4.9A
Total Gate Charge (V <sub>GS</sub> = -10V)	Q <sub>G</sub>	—	21.5	—		
Gate-Source Charge	Q <sub>GS</sub>	—	2.2	—		
Gate-Drain Charge	Q <sub>GD</sub>	—	3.3	—		
Turn-On Delay Time	t <sub>D(ON)</sub>	—	8.7	—	ns	V <sub>DS</sub> = -20V, I <sub>D</sub> = -3.9A V <sub>GS</sub> = -4.5V, R <sub>G</sub> = 1Ω
Turn-On Rise Time	t <sub>R</sub>	—	19.6	—		
Turn-Off Delay Time	t <sub>D(OFF)</sub>	—	34.9	—		
Turn-Off Fall Time	t <sub>F</sub>	—	25.5	—		
Body Diode Reverse Recovery Time	t <sub>RR</sub>	—	9.61	—	ns	I <sub>S</sub> = -3.9A, di/dt = 100A/μs
Body Diode Reverse Recovery Charge	Q <sub>RR</sub>	—	3.3	—	nC	I <sub>S</sub> = -3.9A, di/dt = 100A/μs

- Notes:
- Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.
  - Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1-inch square copper plate.
  - Thermal resistance from junction to soldering point (on the exposed drain pad).
  - I<sub>AS</sub> and E<sub>AS</sub> rating are based on low frequency and duty cycles to keep T<sub>J</sub> = +25°C.
  - Short duration pulse test used to minimize self-heating effect.
  - Guaranteed by design. Not subject to product testing.

Typical Characteristics — N-Channel



V<sub>DS</sub>, DRAIN-SOURCE VOLTAGE (V)  
Fig.1 Typical Output Characteristic



V<sub>GS</sub>, GATE-SOURCE VOLTAGE (V)  
Figure 2. Typical Transfer Characteristic

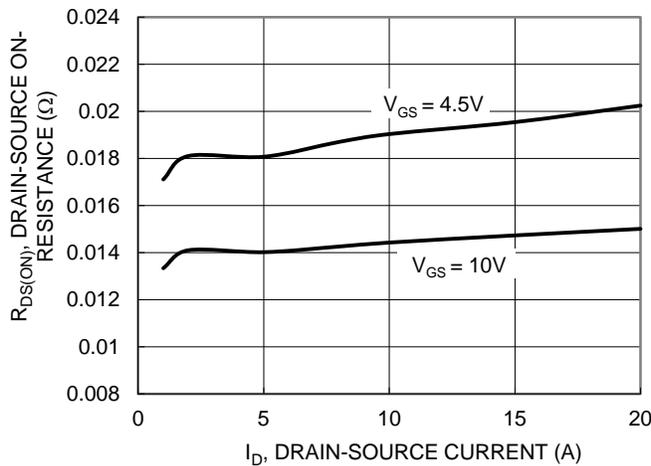
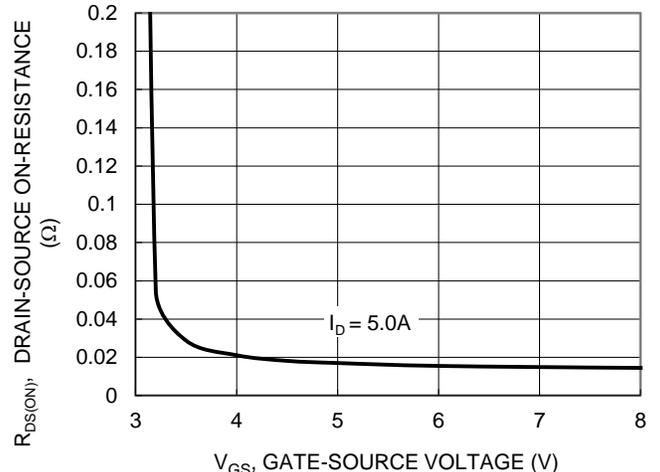


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage



V<sub>GS</sub>, GATE-SOURCE VOLTAGE (V)  
Figure 4. Typical Transfer Characteristic

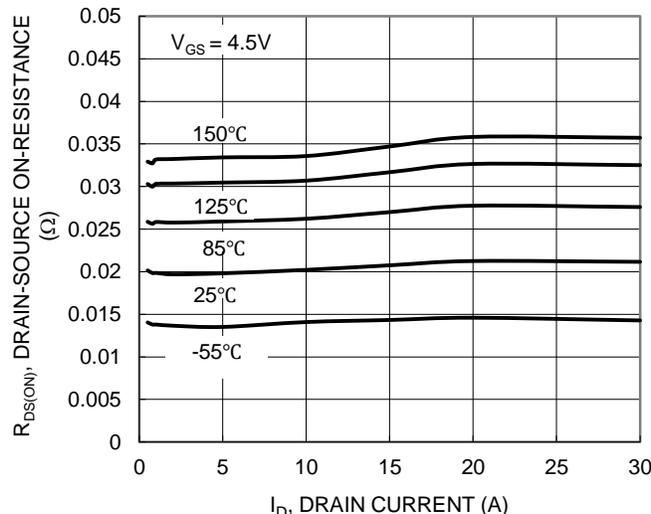


Figure 5. Typical On-Resistance vs. Drain Current and Temperature

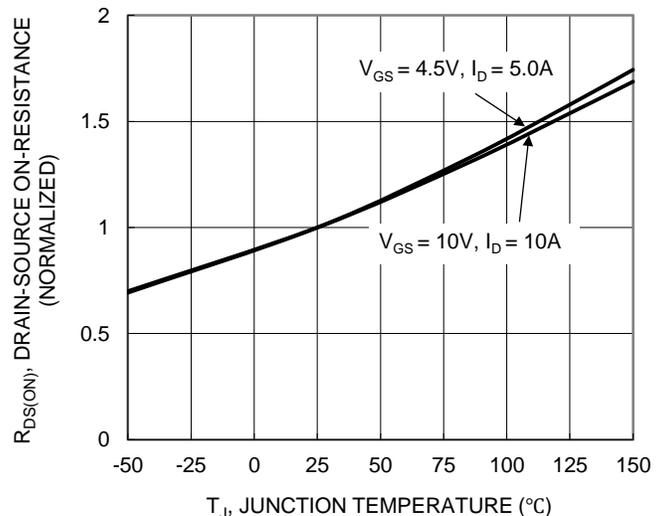


Figure 6. On-Resistance Variation with Temperature

Typical Characteristics — N-Channel (Continued)

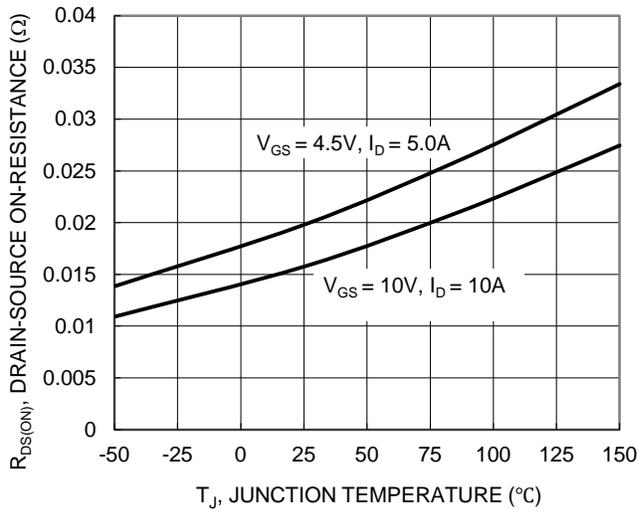


Figure 7. On-Resistance Variation with Temperature

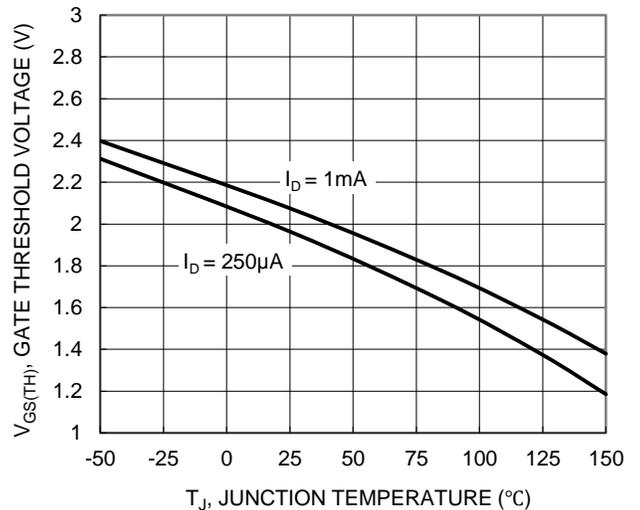


Figure 8. Gate Threshold Variation vs. Temperature

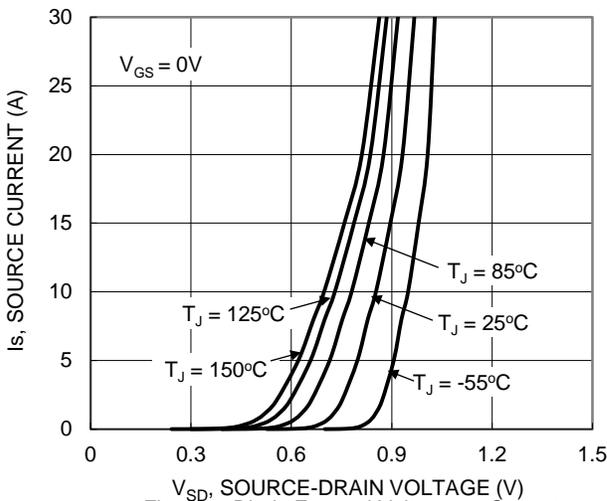


Figure 9. Diode Forward Voltage vs. Current

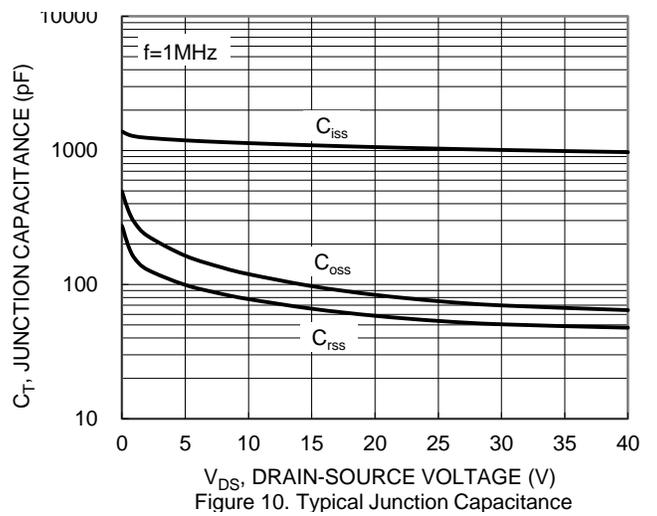


Figure 10. Typical Junction Capacitance

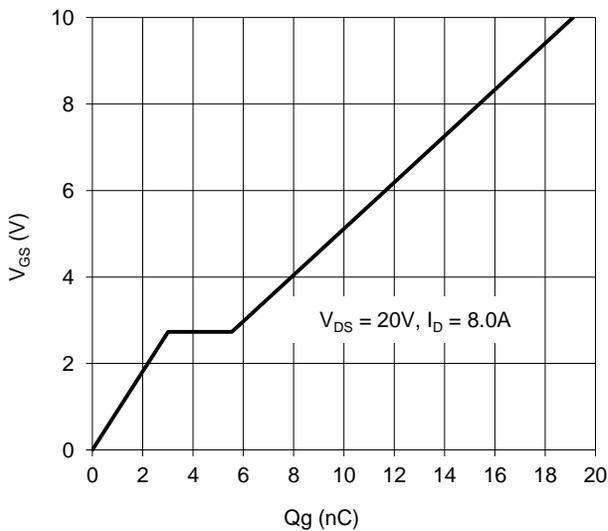


Figure 11. Gate Charge

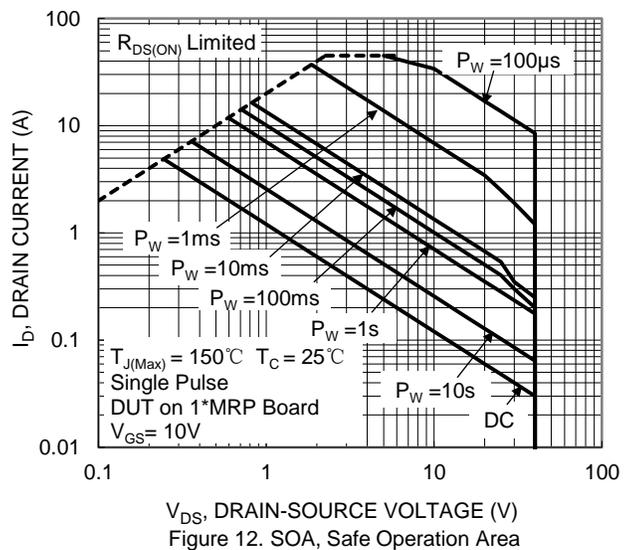


Figure 12. SOA, Safe Operation Area

**Typical Characteristics — P-Channel**

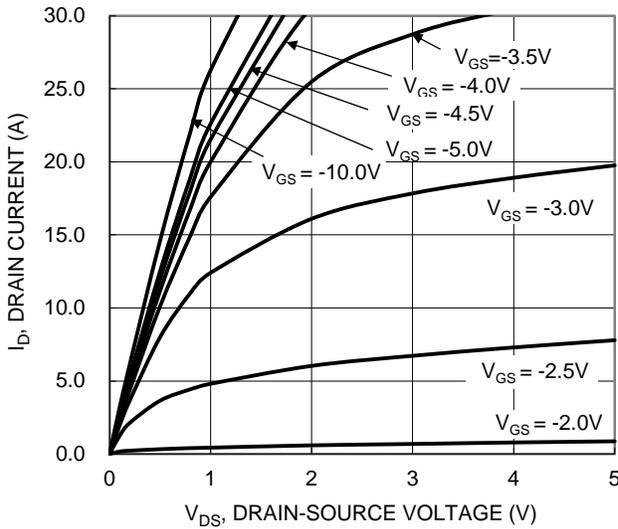


Figure 1. Typical Output Characteristic

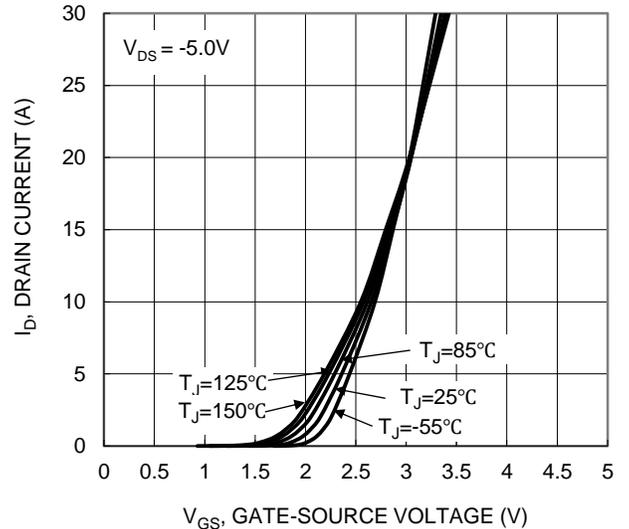


Figure 2. Typical Transfer Characteristic

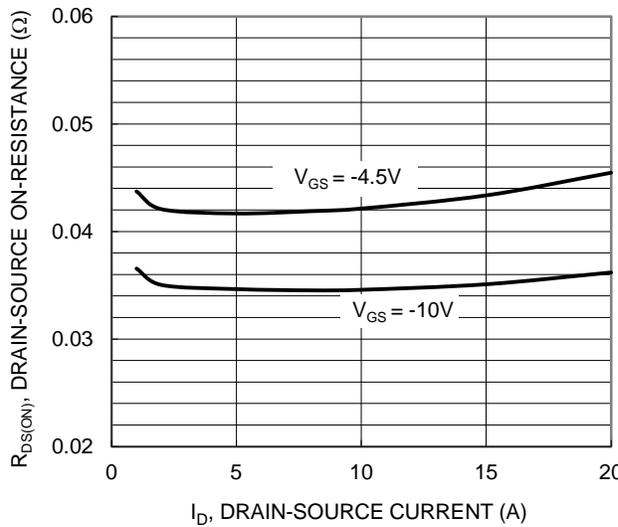


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

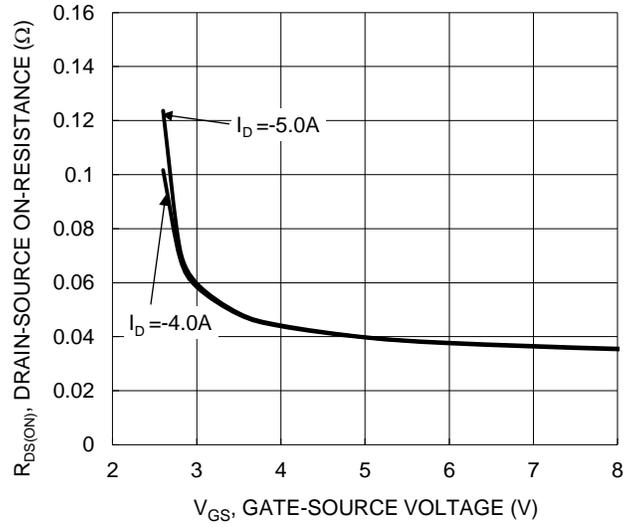


Figure 4. Typical Transfer Characteristic

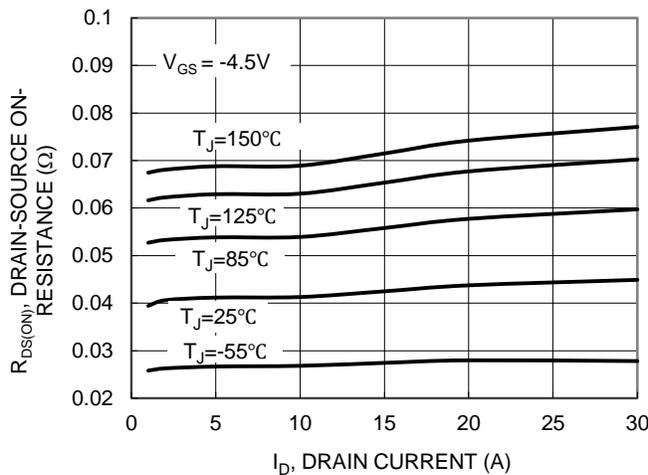


Figure 5. Typical On-Resistance vs. Drain Current and Temperature

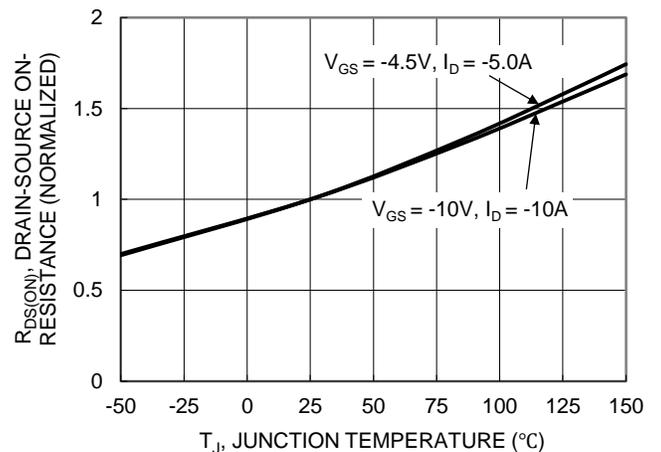


Figure 6. On-Resistance Variation with Temperature

**Typical Characteristics — P-Channel** (Continued)

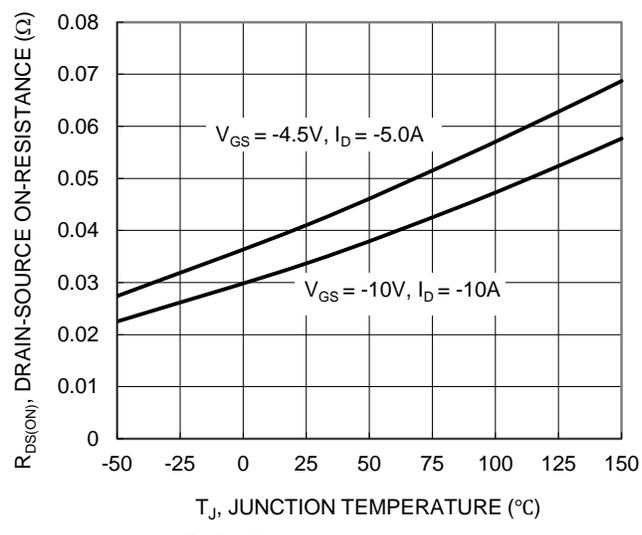


Figure 7. On-Resistance Variation with Temperature

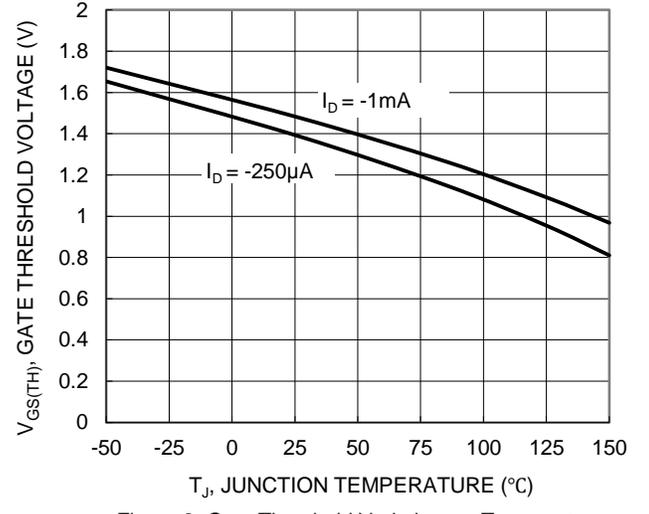


Figure 8. Gate Threshold Variation vs. Temperature

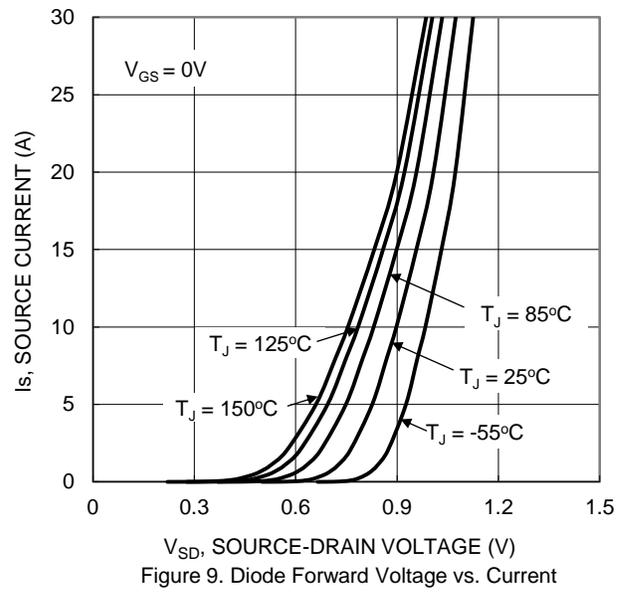


Figure 9. Diode Forward Voltage vs. Current

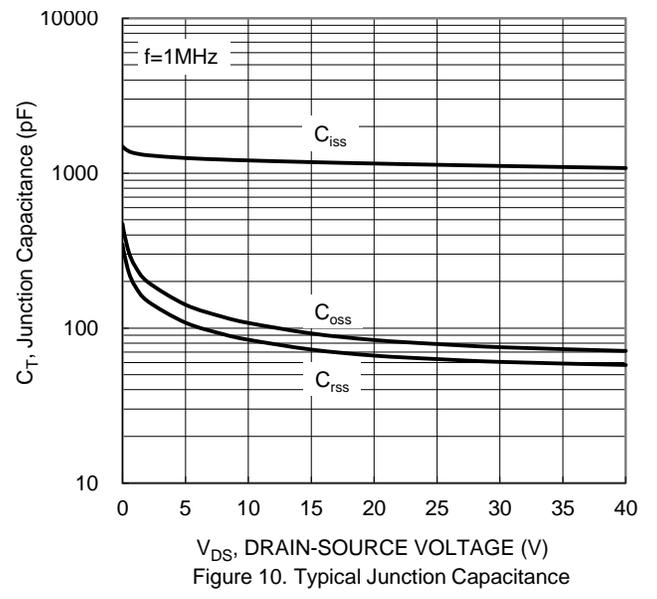


Figure 10. Typical Junction Capacitance

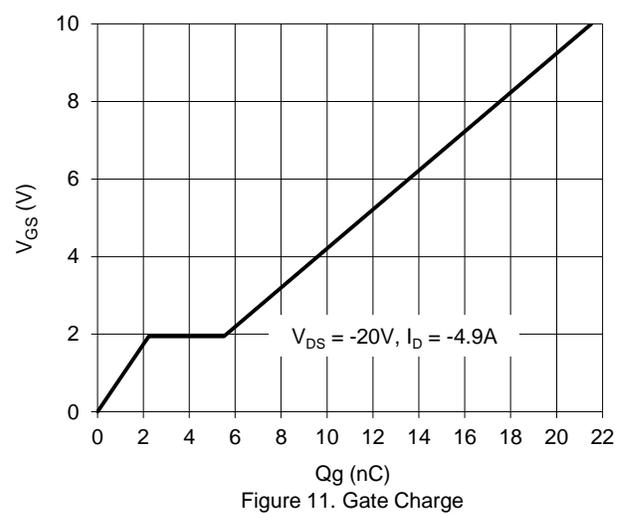


Figure 11. Gate Charge

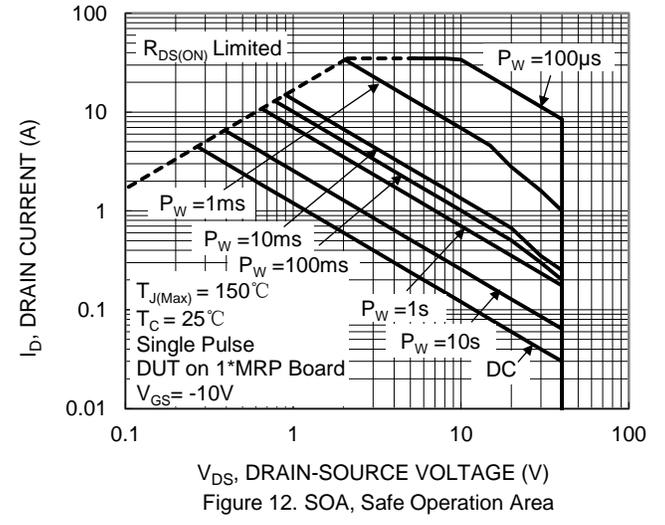


Figure 12. SOA, Safe Operation Area

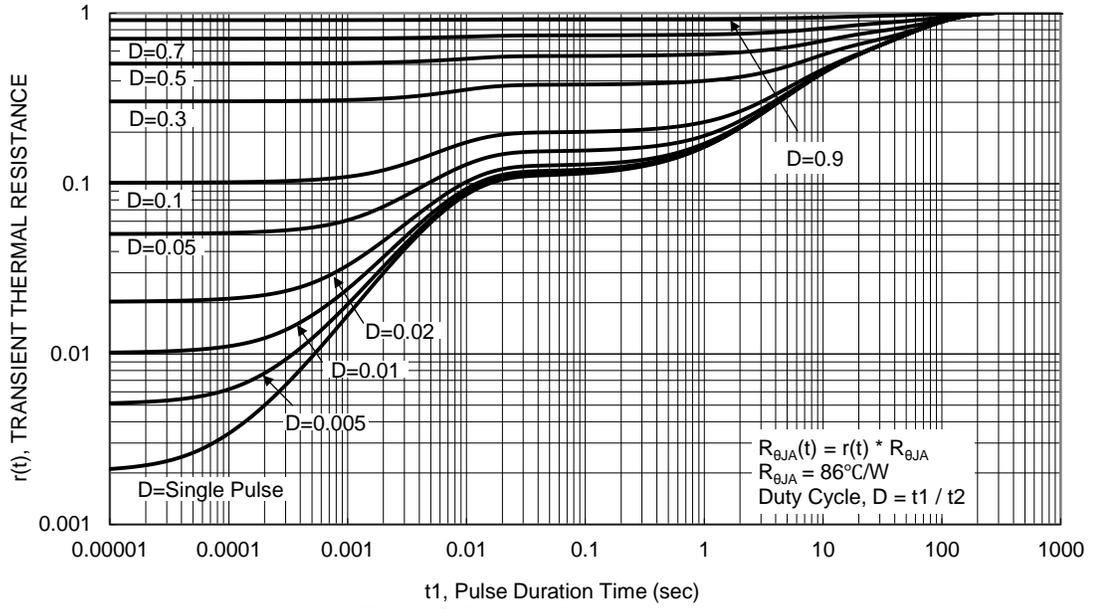
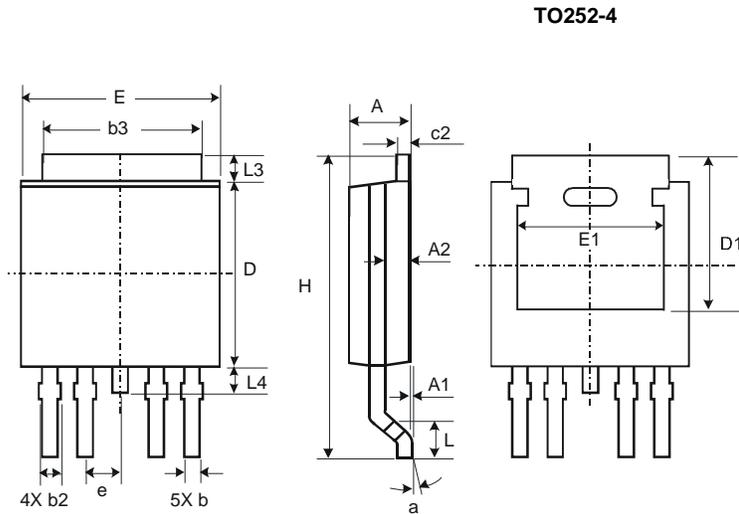


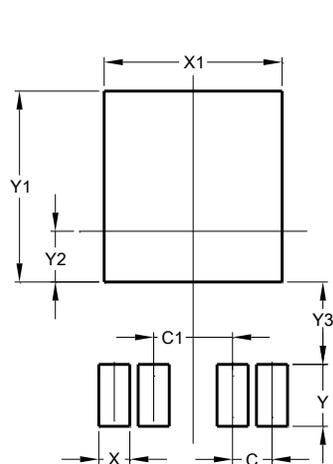
Figure 13. Transient Thermal Resistance

## Package Outline Dimensions



TO252-4			
Dim	Min	Max	Typ
A	2.19	2.39	2.29
A1	0.00	0.13	0.08
A2	0.97	1.17	1.07
b	0.51	0.71	0.583
b2	0.61	0.79	0.70
b3	5.21	5.46	5.33
c2	0.45	0.58	0.531
D	6.00	6.20	6.10
D1	5.21	-	-
e	-	-	1.27
E	6.45	6.70	6.58
E1	4.32	-	-
H	9.40	10.41	9.91
L	1.40	1.78	1.59
L3	0.88	1.27	1.08
L4	0.64	1.02	0.83
a	0°	10°	-
<b>All Dimensions in mm</b>			

## Suggested Pad Layout



Dimensions	Value (in mm)
C	1.27
C1	2.54
X	1.00
X1	5.73
Y	2.00
Y1	6.17
Y2	1.64
Y3	2.66